

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:)
Xiangheng Yang)) Croup: 3661
Serial No.: 09/929,397) Group: 3661)
Filed: August 14, 2001) Examiner:
For: Method for Determining the Intersection of Polygons used to Represent Geographic Features)) Thu V. Nguyen))

FIFTH INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

Pursuant to 37 C.F.R. §1.56 and in conformance with 37 C.F.R. §§ 1.97-1.99, Applicant discloses the reference(s) listed on the attached form PTO-1449 for consideration by the Examiner.

The undersigned certifies that each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior hereto.

Applicant requests that the Examiner review the entire disclosure of each listed reference. The Examiner is requested to acknowledge consideration of the reference(s) by initialing the appropriate location(s) on the form PTO-1449 enclosed herewith.

Included with the submission of this Information Disclosure Statement is a copy of U.S. Patent No. 6,622,085, which is a translation of PCT WO00/43953 (Japanese).

Applicant submits that the claimed subject matter of the present application defines over the cited prior art.

Applicant does not represent any cited reference to be prior art and Applicant reserves the right to disqualify any reference by the showing of an earlier date of invention, if appropriate.

Respectfully submitted,

Frank J. Kozak

Reg. No. 32,908

Attorney for Applicant

NAVTEQ North America, LLC (Formerly NAVIGATION TECHNOLOGIES CORPORATION) 222 Merchandise Mart Plaza, Suite 900 Chicago, Illinois 60654 (312) 894-7000

FORM PTO-1449	SERIAL NO.		CASE NO.
		09/929,397	N0099US
LIST OF PATENTS AND PUBLICATIONS FOR	FILING DATE		GROUP ART UNIT
APPLICANT'S INFORMATION DISCLOSURE		08/14/2001	3661
STATEMENT			
(use several sheets if necessary)	APPLICANT(S):	X. Yang	

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

KEI EKENGE BEGIGKATION			<u> </u>			
EXAMINER		DOCUMENT			CLASS/	FILING
INITIAL		NUMBER	DATE	NAME	SUBCLASS	DATE
	A1	6622085	9/16/2003	Amita et al.	701/208	

FOREIGN PATENT DOCUMENTS

EXAMINER	,	DOCUMENT			CLASS/	TRANS	LATION
INITIAL		NUMBER	DATE	COUNTRY	SUBCLASS	YES	NO
	A2	WO00/43953	7/27/2000	WIPO	G06T 1/00	Х	

EXAMINER INITIAL		OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)
	A3	Yang Y. et al., "An efficient scanning pattern for layered manufacturing processes", Proceedings of the 2001 IEEE International Conference on Robotics and Automation, ICRA 2001, Seoul, Korea 5/21-26/2001, pp. 1340-1345.
DIFE	A4	EP 02255634 Search Report, dated 10/27/2004

NOV 1 8 2004

EXAMINER DATE CONSIDERED.

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.